

Initial Final




Contact Date:	Implementation Date:	Alert Category:	Alert Type:	PCN #:
February 27, 2009	May 28, 2009	Discrete Semiconductors	Additional Wafer Fab Sources	PCN #: 1133
TITLE				
Qualification of additional fab sources for devices listed in the attachment below.				
IMPACT				
None Identified.				
DESCRIPTION OF CHANGE				
This PCN is to notify customers of the qualification of additional wafer fabrication sites in order to assure continuity of supply to our customers. Affected products are listed in the attached table. Full electrical characterization and high reliability testing will be completed on the devices built with the dice from the additional fab sources in order to ensure no change to device functionality or data sheet electrical specifications before shipment to our customers.				
PRODUCTS AFFECTED				
See attached parts list.				
WEB LINKS				
Manufacturer's Notice:	http://www.diodes.com/products/PCNs.shtml			
For More Information Contact:	http://www.diodes.com/contact			
Data Sheet:	http://www.diodes.com/index.php			
DISCLAIMER				
Unless a Diodes Inc. Sales representative is contacted in writing within 30 days of the posting of this notice, all changes described in this announcement are considered approved.				
PCN APPROVAL				
Signatories	Name	Signature	Date	
Signature of Sr. Vice President, Sales & Mktg.	Mark King		February 27, 2009	
Signature of VP Corporate Administration	Ed Tang		February 24, 2009	
Signature of VP Product Development	Francis Tang		February 24, 2009	

Table 1
2N7002-13
2N7002-13-F
2N7002-7
2N7002-7-F
2N7002DW-7-F
2N7002DW-7-F
2N7002E-7
2N7002E-7-F
2N7002T-7-F
2N7002V-7
2N7002VA-7
2N7002VAC-7
2N7002VC-7
2N7002W-7-F
ASMCC0126-7
BS870-13
BS870-7
BS870-7-F
MMBF170-13
MMBF170-7
MMBF170-7-F
2N7002K-7
DMN601DMK-7
DMN601DWK-7
DMN601K-7
DMN601TK-7
DMN601VK-7
DMN601WK-7
2N7002A-7
DMN66D0LDW-7
DMN66D0LT-7